

	Canadian \$
Secondary Ion Mass Spectrometry (SIMS)	
• Cameca IMS-3f with oxygen or caesium source	\$140.00/hour
• ION-TOF TOF-SIMS IV with Ga ⁺ , Cs ⁺ , SF ₅ ⁺ , Ar ⁺ , O ⁺ , and C ₆₀ ⁺ beams, 8" sample stage	\$140.00/hour
X-ray Photoelectron Spectroscopy (XPS)	
• Kratos AXIS Ultra	\$140.00/hour
• Kratos AXIS Nova	\$140.00/hour
Scanning Auger Microscopy (SAM)	
• PHI-660 Scanning Auger Microprobe	\$140.00/hour
Scanning Electron Microscopy (SEM) with Energy Dispersive X-ray (EDX) Spectroscopy	
• LEO 440 SEM equipped with a Quartz XOne Light Element EDX System	\$120.00/hour
• Hitachi S-4500 Field Emission SEM equipped with a Quartz PCI XOne SSD X-ray Analyzer	\$120.00/hour
• Hitachi SU3500 Variable Pressure SEM with a Oxford AZtec X-Max50 SDD X-ray Analyzer	\$120.00/hour
Atomic Force Microscopy (AFM)	
• PSIA XE-100	\$120.00/hour
Surface Profilometry	
• Tencor P-10	\$120.00/hour
Nanomechanical Testing	
• Hysitron TI-950 Triboindenter	\$120.00/hour
Laser Raman Spectroscopy	
• Renishaw 2000	\$140.00/hour
Fourier Transform Infrared (FTIR) Spectroscopy	
• Bruker Tensor II System with Hyperion 2000 Microscope	\$140.00/hour
Optical Microscopy	
• Zeiss Axioplan, Zeiss SteREO Discovery.V8, and Wild M3Z	\$60.00/hour
Contact Angle Goniometry	
• Ramé-Hart 100	\$60.00/hour
Microindentation Hardness Testing	
• Leco LM100	\$60.00/sample
Metallographic Preparation	
• Per sample	\$70.00/sample
Etching	
• Standard	\$70.00/sample
• HF or electrolytic	\$140.00/sample
Priority Service (based on Monday - Friday business hours, excluding weekends and holidays)	
• Five business days	25% surcharge
• Three business days	50% surcharge
• One business day	100% surcharge
Advanced Reporting, Consulting, Data Interpretation, Post-analytical Data Processing, Sample Preparation	
• Hourly basis	\$140.00/hour